

CLAIMS

1. An analog to digital converter ("ADC"), comprising:
5 a band gap reference (BGR) circuit whose
output is internally coupled to an analog input of the
ADC.
2. The ADC of Claim 1, further comprising:
 a positive analog supply voltage (AVDD) and a
10 positive analog reference voltage (REFP) operationally
coupled to a same voltage supply; wherein a BGR value
is used by a CPU as a calibration constant for
determining an AVDD value.
3. The ADC of Claim 1, wherein the ADC can measure the
15 AVDD without using a divider.
4. The ADC of Claim 1, wherein the measured BGR value
is inversely proportional to the AVDD value.
5. A system using a CPU, comprising:
 an analog to digital converter ("ADC"),
20 wherein the ADC includes:
 a band gap reference (BGR) circuit output
internally coupled to an analog input to the ADC.
6. The system of Claim 5, further comprising:
 a positive analog supply voltage (AVDD) and a
25 positive analog reference voltage (REFP) operationally

coupled to same voltage supply; wherein a BGR value is used by the CPU as a calibration constant for determining an AVDD value.

7. The system of Claim 5, wherein the ADC can measure
5 the AVDD without using a divider.

8. The system of Claim 5, wherein the measured BGR value is inversely proportional to the AVDD value.

9. An application specific integrated circuit ("ASIC"), comprising:

10 an analog to digital converter ("ADC"), comprising:

a band gap reference (BGR) circuit whose output is internally coupled to an analog input of the ADC.

15 10. The ASIC of Claim 9, further comprising:

a positive analog supply voltage (AVDD) and a positive analog reference voltage (REFP) operationally coupled to same voltage supply; wherein a BGR value is used by a CPU as a calibration constant for determining
20 an AVDD value.

11. The ASIC of Claim 9, wherein the ADC can measure the AVDD without using a divider.

12. The system of Claim 9, wherein the measured BGR value is inversely proportional to the AVDD value.